

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:

Shambhu Roy

Application No.:

Group Art Unit:

Filed: April 13, 2004

Examiner:

For: MICRO THERMAL CHAMBER HAVING PROXIMITY CONTROL TEMPERATURE  
MANAGEMENT FOR DEVICES UNDER TEST

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information that the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:

- 1a. ☒ Form PTO-1449.
- 1b. ☒ Copies of IDS citations
- 1c. ☐ An English language copy of search report(s) from a counterpart foreign application or a PCT International Search Report.
- 1d. ☐ English language translation (complete or relevant portion(s)) attached to each non-English language publication.
- 1e. ☐ Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.

2. ☐ In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is

(Check appropriate Items 2a, 2b, 2c and/or 2d)

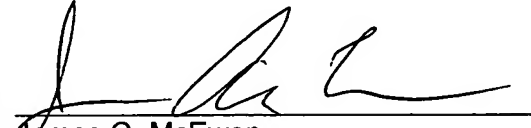
- 2a. ☐ satisfied because all non-English language publications were cited on the enclosed "English-language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, pp. 600-100 to 600-101, Rev. 1, Feb. 2000.)
- 2b. ☐ set forth in the application.

- 2c. ☐ satisfied because an English language translation (complete or relevant portion(s)) is attached to each non-English language publication.
- 2d. ☐ enclosed as Attachment 1(e), hereto.
3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

STAAS & HALSEY LLP

Dated: April 13, 2004  
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By:   
James G. McEwen  
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FORM PTO-1449 <div style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</div> <div style="text-align: center;"><b>LIST OF REFERENCES CITED BY APPLICANT</b></div> <div style="text-align: center;"><i>(Use several sheets if necessary)</i></div>	ATTORNEY DOCKET NO. 1526.1005	APPLICATION NO.
FIRST NAMED INVENTOR Shambhu Roy		
FILING DATE April 13, 2004		GROUP ART UNIT

### U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA	5,821,505	10/13/98	Tustaniwskyj et al.			4/4/97
	AB	5,844,208	12/1/98	Tustaniwskyj et al.			4/4/97
	AC	5,966,940	10/19/99	Gower et al.			11/18/97
	AD	6,091,062	7/18/00	Pfahnl et al.			1/27/98
	AE						
	AF						

### FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							

### OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

			TRANSLATION YES NO
	AM		
	AN		
	AO		
EXAMINER		DATE CONSIDERED	
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

## ATTACHMENT 1(g)

<b>LIST OF ADDITIONAL SUBMITTED DOCUMENTS</b>	ATTORNEY DOCKET NO.	APPLICATION NO.
	1526.1005	
	FIRST NAMED INVENTOR	
	Shambhu Roy	
	FILING DATE	GROUP ART UNIT
	April 13, 2004	

The following document(s) is/are listed in accordance with the duty of disclosure provisions of 37 CFR § 1.56, so that the Examiner may consider same should he deem any thereof to be material to examination of the subject application. Pursuant to 37 CFR 1.98(a)(2)(iii), a copy of any identified copending application(s) is provided.

It is requested that the Examiner acknowledge his consideration of document(s) below-listed by initialling same in the space provided adjacent each such application and that the Examiner sign and date this form at the bottom thereof to confirm such consideration having been given.

**This submission in no way represents an admission that any of the information listed herein constitutes prior art with respect to the subject application and unless and until such prior art status is established, this submission is not a request that the information presented herein be printed on the face of any patent issuing from the subject application in which this information is being filed.**

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO	
	AC							
	AD							

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

							TRANSLATION YES NO	
	AE	<a href="http://www.aetrium.com/mdtx32.htm">http://www.aetrium.com/mdtx32.htm</a> ; <i>Model DTX Series Dynamic Temperature Pick-And-Place IC Test Handler</i> , pp. 1- 4						
	AF	<a href="http://www.deltad.com/products/autotest/pickplace_summit.htm">http://www.deltad.com/products/autotest/pickplace_summit.htm</a> ; <i>Delta Design Products: Automated Test Handlers: Pick &amp; Place Summit Handler</i>						
	AG	<a href="http://www.testandmeasurement.com/Content/ProductShowcase/product.asp?DOCID;">http://www.testandmeasurement.com/Content/ProductShowcase/product.asp?DOCID;</a> <i>Test and Measurement.Com, Schlumberger introduces IHS 1100 test handler with advanced thermal control</i> ; pp. 1 & 2						

EXAMINER	DATE CONSIDERED
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	